

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,560	CHOU ET AL.	
Examiner	Art Unit	
Sam K. Ahn	2611	

SEARCHED					
Class	Subclass	Date	Examiner		
375	229, 230, 232 233, 346, 348 350, 354, 355 364, 373	1	1		
370	364, 373 516, 518, 519 520				
379	340, 398				
455	63.1,114.2				
708	323	2/4	a		
	·				
	·				
		-			

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST- inventor scench Keyword and attaion searce Ittt and google Keyword and atation scend Consulted Young Tse 374 P.E	1 1	a		
consulted Young Tse 375 P.E	· 2 /4	an		
,				
•				
